

April 2000

# **FQA44N30**

## 300V N-Channel MOSFET

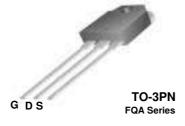
### **General Description**

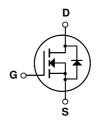
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supply.

#### **Features**

- 43.5A, 300V,  $R_{DS(on)}$  = 0.069 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 120 nC)
- Low Crss (typical 75 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQA44N30	Units	
V <sub>DSS</sub>	Drain-Source Voltage		300	V	
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C) - Continuous (T <sub>C</sub> = 100°C)		43.5	Α	
			27.5	Α	
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	174	Α	
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	1700	mJ	
I <sub>AR</sub>	Avalanche Current	(Note 1)	43.5	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	31	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns	
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		310	W	
	- Derate above 25°C		2.5	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.4	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

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Symbol	Parameter	Test Conditions	i	Min	Тур	Max	Units
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		300			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced	to 25°C		0.32		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 300 V, V <sub>GS</sub> = 0 V				1	μА
		V <sub>DS</sub> = 240 V, T <sub>C</sub> = 125°C				10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V		-		-100	nA
On Cha	aracteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 21.75 A			0.055	0.069	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 50 V, I <sub>D</sub> = 21.75 A	(Note 4)		30		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			810 75	1050 95	pF pF
	,				10	30	ρı
	ing Characteristics	T			0.5	400	
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 150 \text{ V}, I_{D} = 43.5 \text{ A},$ $R_{G} = 25 \Omega$ (Note 4, 5)		-	85	180	ns
t <sub>r</sub>	Turn-On Rise Time			-	470	950	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			-	240	490	ns
t <sub>f</sub>	Turn-Off Fall Time				230	470	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 240 \text{ V}, I_D = 43.5 \text{ A}$	,		120	150	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V (Note 4, 5)			29		nC
Q <sub>gd</sub>	Gate-Drain Charge		(11010 1, 0)		58		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings	S				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current			ı		43.5	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	orward Current		-		174	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 43.5 \text{ A}$		-		1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 43.5 \text{ A},$		ı	320		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs	(Note 4)		3.26		μС

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 1.5mH, I<sub>AS</sub> = 43.5A, V<sub>DD</sub> = 50V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub>  $\leq$  43.5A, di/dt  $\leq$  200A/μs, V<sub>DD</sub>  $\leq$  BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width  $\leq$  300μs, Duty cycle  $\leq$  2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

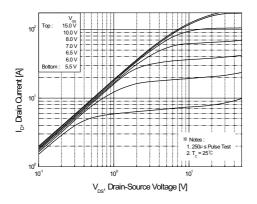


Figure 1. On-Region Characteristics

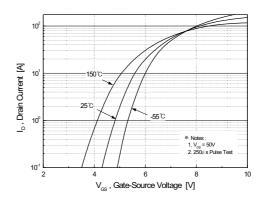


Figure 2. Transfer Characteristics

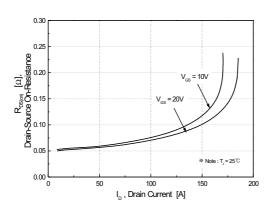


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

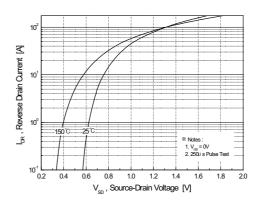


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

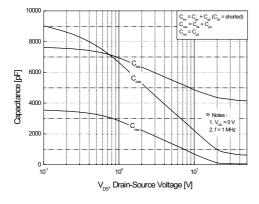


Figure 5. Capacitance Characteristics

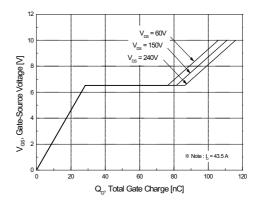
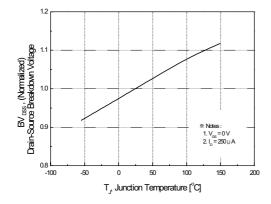


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)



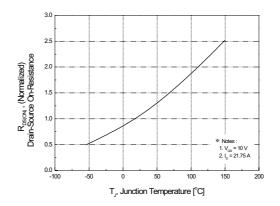
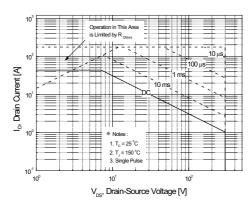


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



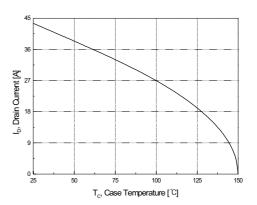


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

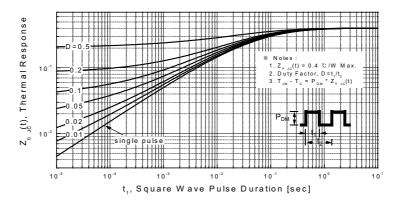
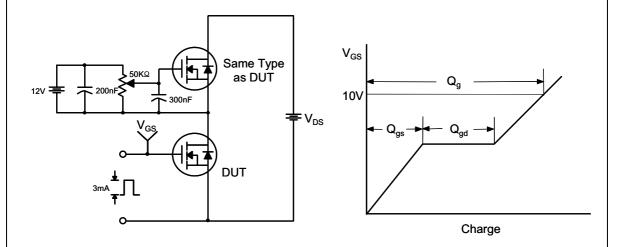


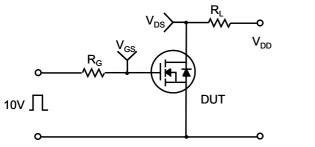
Figure 11. Transient Thermal Response Curve

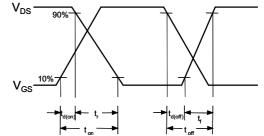
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## **Gate Charge Test Circuit & Waveform**

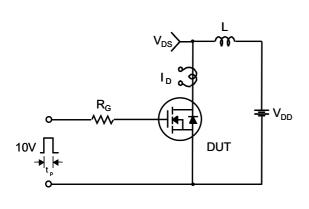


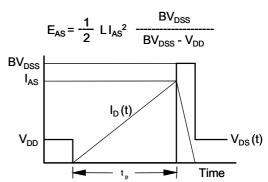
# **Resistive Switching Test Circuit & Waveforms**



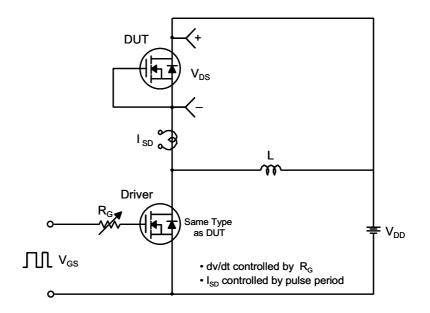


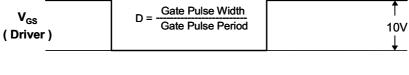
## **Unclamped Inductive Switching Test Circuit & Waveforms**

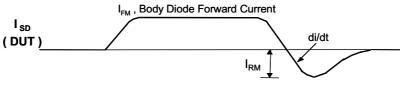




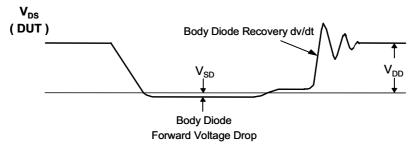
### Peak Diode Recovery dv/dt Test Circuit & Waveforms







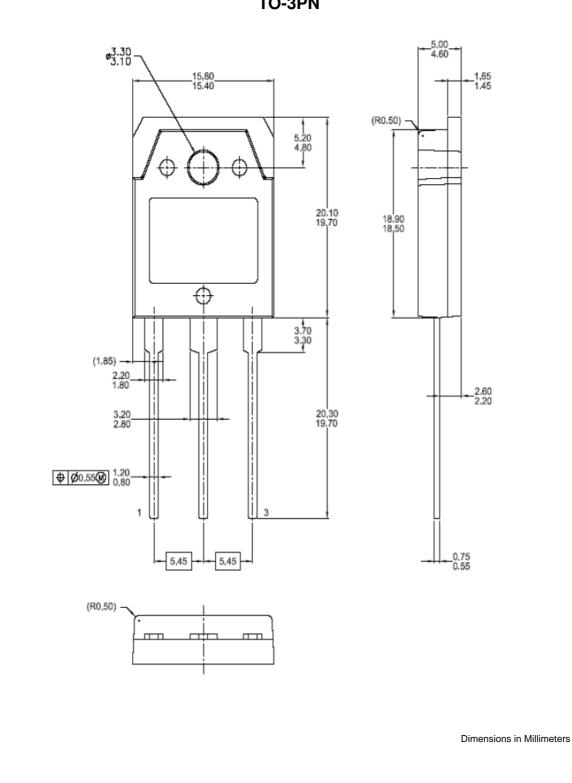
Body Diode Reverse Current



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# **Mechanical Dimensions**

TO-3PN



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